## Single-shot electro-optic longitudinal profile of sub-ps bunches

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- Single-shot electro-optic detection of ultra-short bunches
  - spectral-decoding
  - temporal decoding
- FELIX electron bunch measurements real time bunch profile adjustment bunch timing jitter charge dependence
- Sub-100fs bunch diagnostic ?





#### Single-shot EO measurement of Coulomb field



# Effective polarisation rotation proportional to coulomb field





### Electro-optic detection of the Coulomb field: 'Spectrometer method'

(Spectral decoding)







#### Time-resolution of spectral decoding.



Mixing of optical spectrum with neighbouring frequencies optical spectral modulation unreliable with resolution greater than modulation bandwidth



Electro-optic longitudinal beam-profile diagnostics, Steve Jamison ELAN, May 2004



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#### Time-resolution function NOT a smoothing function. Can cause artifacts!! CANNOT BE TREATED AS RMS TIME-RESOLUTION Should be considered as temporal *limitation*

e.g balanced detection: measure change in probe spectrum...

$$S(\omega) = \left|\overline{E}_{opt}(\omega)\right|^{2} - \left|\overline{E}_{opt}(\omega) - \overline{E}_{Coul}(\omega)\right|^{2}$$

$$\left|\overline{E}_{opt}(\omega)\right|^{2} \left(\underline{E}_{Coul}(\tau + t_{0}) - \cos(\tau^{2}/\alpha - \pi/4)\right)$$
where  $\tau = 2\alpha(\omega - \omega_{0})$ 

$$\int_{-10}^{10} \int_{-5}^{0} \int_{\tau = 2\alpha(\omega - \omega)}^{10} \int_{\tau = 2\alpha(\omega$$





Oscillations due to spectral-encoding artifact?

Jamison et al. Opt. Lett. **18** 1710 (2003)

#### Observe oscillating features on shorter time scale than usual "time resolution"

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#### (Temporal decoding) Electro-optic detection of Coulomb field: 'Cross correlation method'



Temporal to spatial mapping of optical probe pulse

- Avoids problems of inseparability of frequency-time ٠
- *Decoding* time-resolution ~ 30fs ullet





### Single-shot "temporal decoding" of optical probe



Temporal profile of probe pulse \_ Spatial image of SHG





#### 30-50MeV electron beam measurements FELIX FEL facility, Rijnhuizen, Netherlands







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# Comparison of temporal and spectral decoding at FELIX



Electro-optic longitudinal beam-profile diagnostics, Steve Jamison ELAN, May 2004 Confirms time resolution improvements of TD technique

#### Degradation of SD signal in excellent agreement with calculation

NO free parameters in SD calculation – based on bunch profile inferred from TD and measured laser parameters.







by varying bunch charge ( EO signal  $Q^2$  )





#### EO measurement of bunch timing jitter (FELIX, December 2003)





#### Real time monitoring and bunch profile modification... (FELIX, December 2003)



Bunch profile modified by changing the buncher and accelerator phase.





#### Need even better time-resolution.... (measuring sub-200fs bunches) .

Optical spectrum-envelope interdependence

EO phase matching

EO crystal absorption

>300fs bunch duration limitation
Solved by envelope-cross-correlation
~30-50fs possible (?)

>200fs limitation for undistorted measurement Rigorous retrieval of true field possible

Alternative EO materials. (GaP, GaSe, DAST...) Approximate interpolation... ~30fs possible (?)

Coulomb field angle

100 MeV electrons~ 30 fs @ 1 mm distanceImproves with higher energy beams

Optical bandwidth

Time resolution approx. optical pulse duration. ~30 fs. Improvements through X-FROG, ....?





#### Inclusion of perturbing effect of dielectric crystal

"slowed down" Coulomb field is what we wish to measure

the probe pulse velocity is reduced by a very similar factor



#### Calculation only applied to region inside the crystal.

The fields outside the crystal are the "freespace" Coulomb Fields, and only shown to provide an indication of the relative position of the electron.





### EO Phase matching limitations

Able to measure fast oscillations ....



But...

Different frequency components measured with different efficiency and different phase

# Raw measurement does not correspond to Coulomb field

Electro-optic longitudinal beam-profile diagnostics, Steve Jamison ELAN, May 2004 ~30fs oscillations measured with E.O. effect in ZnTe EO crystal

Q. Wu, X.-C. Zhang Appl. Phys. Lett **71** 1285 (1997)

$$S(t) = E_{THz}(-)f(-)e^{i-t} d$$

where

$$f(\ ) \qquad \frac{\exp(i\omega(n_{opt} - n_{THz})L/c) - 1}{i\omega(n_{opt} - n_{THz})/c}$$





#### Summary.....

- Demonstrated non-destructive longitudinal profile measurement with 650fs FWHM bunches.
- Estimated bunch time resolution ~200fs
- Real-time bunch shape monitoring and adjustment
- Challenges remain in getting sub-100fs resolution (materials, data deconvolution, optical bandwidth, ...)





#### What next?.... (wish list)

- Testing of diagnostic on shorter bunches (and higher energy)
- Bench marking of diagnostic
- Combined transverse & longitudinal profile (single shot, non-destructive)





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#### Bunch profile from EO signal...



#### for thin crystals, EO detection efficiency ~ constant over all frequencies 300fs 1ps 200fs 3.0 1.0 EO detection efficiency Direct measurement accurately L = 0.1 mm 0.8 represents Coulomb field 2.5 Selative Units 0.6 L = 0.5 mmL = 2 mm0.4 ତ୍ର 1.5 × Typically use 0.5mm thick ZnTe ~300fs 0.2 1.0 2 Frequency [THz]

G. Gallot et al. App. Phys. Lett. 74 3450 (1999)

for faster field oscillations, can formally deconvolve the material response, and obtain the true electric field profile





#### EO absorption... missing data



Appl. Phys. Lett, Q. Wu, X-C Zhang 71 1285 (1997)

Limits ability to recover true electric field.

- different materials (GaP, GeSe,...)
- •Interpolation of data through missing region





#### Spectral bandwidth limitations

• Amplitude modulation of carrier wave implicitly creates "side-band" frequencies

$$\overline{E}_{Opt}(\omega) \quad \overline{E}_{Coul}(\omega) = d \quad \left[ \overline{E}_{Opt}(\omega + \omega) \overline{E}_{Coul}^{*}(\omega + \omega) \overline{E}_{Coul}(\omega - \omega) \overline{E}_{Coul}(\omega - \omega) \overline{E}_{Coul}(\omega - \omega) \right] ; \text{for } \omega > 0;$$

Mixing of optical spectrum with neighbouring frequencies ∓ optical spectral modulation unreliable with resolution greater than modulation bandwidth

$$\begin{array}{ll} approximate \text{ temporal resolution} \\ \text{based on bandwidth} \end{array} > (t_{o}t_{chirped})^{1/2} \end{array}$$





#### **Optical bandwidth limitations**

EO effect as retardation based on sum and frequency mixing between optical and THz frequencies. Breakdown in use of polarisation rotation as diagnostic when modulation bandwidth>> optical bandwidth

Cross-correlator time resolution limited by transform limited optical pulse

Frequency resolved optical gating (FROG) techniques ?





#### 30-50MeV electron beam measurements FELIX FEL facility, Rijnhuizen, Netherlands



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#### Why do we need an ultrafast electron bunch diagnostic? Plasma wakefield acceleration



How to measure bunch synchronism? Bunch duration? Temporal profile?

What is temporal structure of both injected and

accelerated beam? Electro-optic longitudinal beam-profile diagnostics, Steve Jamison ELAN, May 2004





Second-harmonic generation (single shot) cross-correlation

Time window, :

Beam diameter, *D*Angle of incidence

$$\tau = 2D \sin()/c$$
9ps for D=5mm, 15

Phase matching in BBO achievable for incident angles  $< 33^{\circ}$ 

Non-standard crystal geometry 400nm "walk-off" orthogonal to time-axis

**BBO c-axis** 











National Synchrotron Light Source at Brookhaven National Laboratory (Source Development Laboratory )



H. Loos., et al, May 2003 Particle accelerator Conference PAC-2003

Oscillations due to spectral-encoding artifact?

EO diagnostic being setup on TESLA test accelerator

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